

**MATERIALS RESEARCH SOCIETY**  
**SYMPOSIUM PROCEEDINGS VOLUME 1691**

# **Materials for End-of-Roadmap Devices in Logic, Power and Memory**

April 21-25, 2014  
San Francisco, California, USA

**Printed from e-media with permission by:**

Curran Associates, Inc.  
57 Morehouse Lane  
Red Hook, NY 12571  
[www.proceedings.com](http://www.proceedings.com)

**ISBN: 978-1-5108-0550-7**

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Cambridge, New York, Melbourne, Madrid, Cape Town,  
Singapore, São Paulo, Delhi, Tokyo, Mexico City

Cambridge University Press  
32 Avenue of the Americas, New York, NY 10013-2473, USA  
[www.cambridge.org](http://www.cambridge.org)

Materials Research Society  
506 Keystone Drive, Warrendale, PA 15086  
[www.mrs.org](http://www.mrs.org)

CODEN: MRSPDH

ISBN: 978-1-5108-0550-7

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## TABLE OF CONTENTS

<b>Nuclear Magnetic Resonance as a Probe of the Topological Insulator Bi<sub>2</sub>Se<sub>3</sub></b> .....	1
<i>D. Nisson, A. Dioguardi, P. Klavins, C. Lin, K. Shirer, A. Shockley, J. Crocker, N. Curro</i>	
<b>Electroforming Of Fe:STO Samples For Resistive Switching Made Visible By Electrocoloration Observed By High Resolution Optical Microscopy</b> .....	7
<i>V. Havel, A. Marchewka, S. Menzel, S. Hoffmann-Eifert, G. Roth, R. Waser</i>	
<b>Dielectric Morphology and RRAM Resistive Switching Characteristics</b> .....	13
<i>G. Bersuker, B. Butcher, D. Gilmer, L. Larcher, A. Padovani, R. Geer, P. Kirsch</i>	
<b>Nonvolatile Memories based on AlO<sub>x</sub> Embedded ZrHfO High-k Gate Dielectric</b> .....	25
<i>S. Zhang, Y. Kuo, X. Liu, C. Lin</i>	
<b>Resistive Switching Behavior and Electrical Properties of TiO<sub>2</sub>:Ho<sub>2</sub>O<sub>3</sub> and HoTiO<sub>x</sub> Based MIM Capacitors</b> .....	31
<i>H. Garcia, H. Castan, S. Duenas, E. Perez, L. Bailon, K. Kukli, M. Ritala, M. Leskela</i>	
<b>Pioneering Application of Corona Charge-Kelvin Probe Metrology to Noncontact Characterization of In<sub>0.53</sub> Ga<sub>0.47</sub> As/Al<sub>2</sub>O<sub>3</sub>/HfO<sub>2</sub> Stack</b> .....	37
<i>A. Savtchouk, J. D'Amico, M. Wilson, J. Lagowski, W. Wang, T. Kim, G. Bersuker, D. Veksler, D. Koh</i>	
<b>Ultra-Low-Energy Straintronics Using Multiferroic Composites</b> .....	45
<i>K. Roy</i>	
<b>The Effect of Multiple Interfaces on the Electrical Properties of MgO/Al<sub>2</sub>O<sub>3</sub> Multilayer Gate Stacks on Si Grown by MBE</b> .....	51
<i>C. Su, M. Menghini, J. Seo, J. Locquet</i>	
<b>A Frequency Agile Miniaturized Antenna Utilizing Ferroelectric Barium-Strontium-Titanate Capacitors</b> .....	56
<i>S. Alzahrani, T. Kalkur, H. Song</i>	
<b>A Tunable Bandstop Filter Using Thin Film Barium-Strontium-Titanate Varactors</b> .....	63
<i>S. Alzahrani, T. Kalkur</i>	
<b>The Influence of Water Absorbed in Grain Boundary of a Polycrystalline NiO Layer on the Memory Characteristics of Pt/NiO/Pt Resistive Random Access Memory (ReRAM)</b> .....	69
<i>R. Ogata, M. Yoshihara, N. Murayama, S. Kishida, K. Kinoshita</i>	
<b>Author Index</b>	